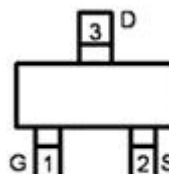
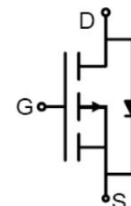


**Main Product Characteristics:**

$V_{DSS}$	-30V
$R_{DS(on)}$	52mΩ(typ)
$I_D$	-4A


**SOT-23**

**Pin Assignments**

**Schematic Diagram**
**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


**Description:**

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

**Absolute Max Rating:**

Symbol	Parameter	Max.	Units
$I_D @ TC = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ①	-4	A
$I_{DM}$	Pulsed Drain Current ②	-16	
$P_D @ TC = 25^\circ C$	Power Dissipation ③	1.2	W
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 12$	V
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	$^\circ C$

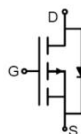
## Thermal Resistance

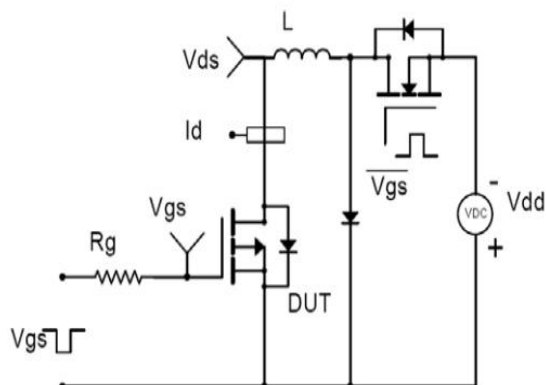
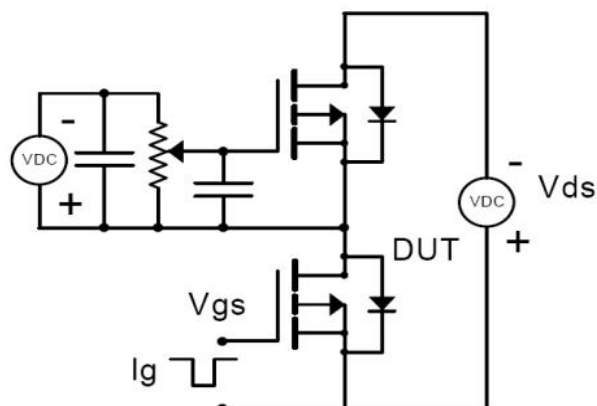
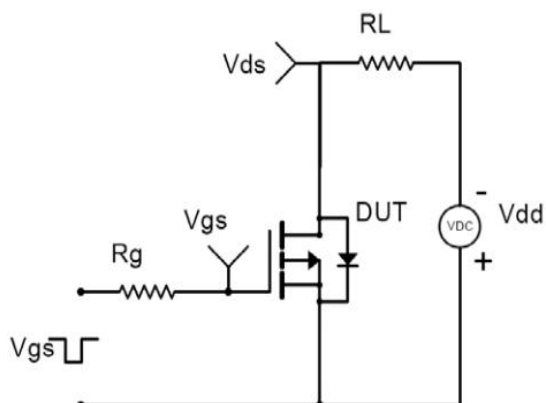
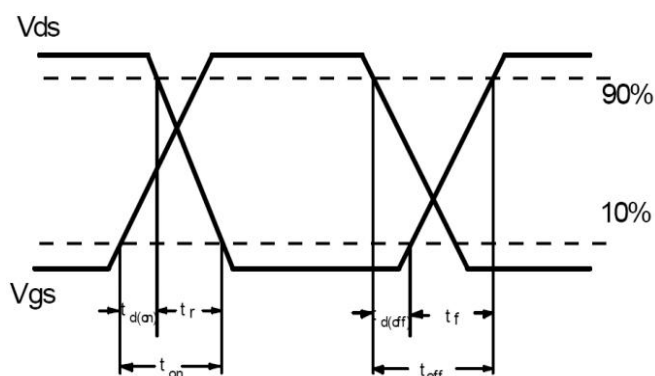
Symbol	Characterizes	Typ.	Max.	Units
R <sub>θJA</sub>	Junction-to-Ambient (t ≤ 10s) ④	—	108	°C/W

## Electrical Characteristics @T<sub>A</sub>=25°C unless otherwise specified

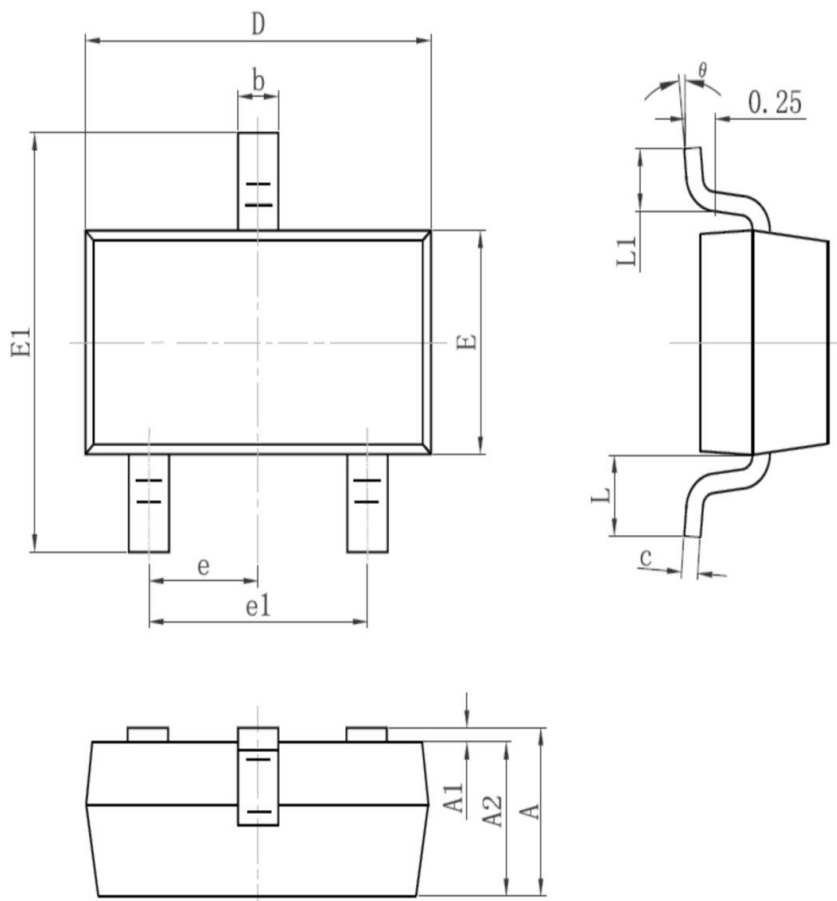
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	-30	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	—	52	68	mΩ	V <sub>GS</sub> =-10V, I <sub>D</sub> = -3.8A
		—	62	80	mΩ	V <sub>GS</sub> =-4.5V, I <sub>D</sub> = -3A
V <sub>GS(th)</sub>	Gate threshold voltage	-0.6	—	-1.3	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
I <sub>DSS</sub>	Drain-to-Source leakage current	—	—	-1	μA	V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V
I <sub>GSS</sub>	Gate-to-Source forward leakage	—	—	100	nA	V <sub>GS</sub> = 12V
	Gate-to-Source reverse leakage	—	—	-100		V <sub>GS</sub> = -12V
Q <sub>g</sub>	Total gate charge	—	6.7	—	nC	I <sub>D</sub> = -3A
Q <sub>gs</sub>	Gate-to-Source charge	—	1.5	—		V <sub>DD</sub> =-15V
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	—	1.8	—		V <sub>GS</sub> = -10V
t <sub>d(on)</sub>	Turn-on delay time	—	11	—	ns	V <sub>GS</sub> =-4.5V,
t <sub>r</sub>	Rise time	—	84	—		V <sub>DS</sub> = -15V,
t <sub>d(off)</sub>	Turn-Off delay time	—	152	—		R <sub>GEN</sub> =3Ω
t <sub>f</sub>	Fall time	—	360	—		I <sub>D</sub> = -3A
C <sub>iss</sub>	Input capacitance	—	365	—	pF	V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output capacitance	—	40	—		V <sub>DS</sub> = -15V
C <sub>rss</sub>	Reverse transfer capacitance	—	34	—		f = 1MHz

## Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode) ①	—	—	-4	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode)	—	—	-16	A	
V <sub>SD</sub>	Diode Forward Voltage	—	—	-1.2	V	I <sub>S</sub> =-4A, V <sub>GS</sub> =0V, T <sub>J</sub> = 25°C
t <sub>rr</sub>	Reverse Recovery Time	—	36	—	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = -3A,
Q <sub>rr</sub>	Reverse Recovery Charge	—	5	—	nC	di/dt = 100A/μs

**Test Circuits and Waveforms:**
**EAS Test Circuit:**

**Gate Charge Test Circuit:**

**Switching Time Test Circuit:**

**Switching Waveforms:**

**Notes:**

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Mechanical Data:**
**SOT-23 PACKAGE OUTLINE DIMENSION**


Symbol	Dimension In Millimeters		Dimension In Inches	
	Min	Max	Min	Max
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.95TYP		0.037TYP	
e1	1.800	2.000	0.071	0.079
L	0.55REF		0.022REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

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